TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2173

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain-source ON resistance : RDS (ON) = $13 \text{ m}\Omega$ (typ.)

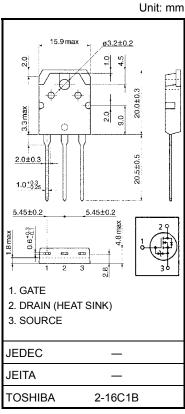
 $\bullet~$ High forward transfer admittance ~ : $|\,Y_{fs}\,|$ = 40 S (typ.)

• Low leakage current : $I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(V_{DS} = 60 \,\text{V})$

• Enhancement mode : $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	60	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	60	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	I _D	50	Α
Drain current	Pulse (Note 1)	I _{DP}	200	Α
Drain power dissipation	n (Tc = 25°C)	P _D	125	W
Single pulse avalanche energy (Note 2)		E _{AS}	683	mJ
Avalanche current		I _{AR}	50	Α
Repetitive avalanche	energy (Note 3)	E _{AR}	12.5	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature r	ange	T _{stg}	-55~150	°C



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.0	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 371 μ H, R_G = 25 Ω , I_{AR} = 50 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



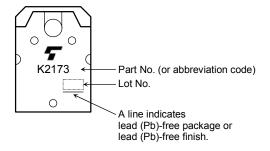
Electrical Characteristics (Ta = 25°C)

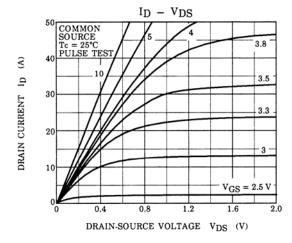
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V
Gate threshold v	oltage/	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = 4 V, I _D = 25 A	_	19	25	mO
			V _{GS} = 10 V, I _D = 25 A	_	13	17	mΩ
Forward transfer	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 25 A	28	40	_	S
Input capacitano	e	C _{iss}		_	3550	_	
Reverse transfer capacitance		C _{rss}		_	550	_	pF
Output capacitance		Coss		_	1600	_	
Switching time	Rise time	t _r	$V_{GS} \stackrel{10V}{\underset{0V}{\text{OV}}} \stackrel{I_{D}=25\text{A}}{\underset{R_{L}=\\1.2\Omega}{\text{V}}} V_{OUT}$ $V_{DD} = 30V$ $Duty \leq 1\%, \ t_{W} = 10\mu\text{s}$	_	25	_	
	Turn-on time	t _{on}		_	55	_	nc
	Fall time	t _f		_	60	_	- ns
	Turn-off time	t _{off}		_	180	_	
Total gate charge (Gate-source plus gate-drain)		Qg			110	_	
Gate-source charge		Q _{gs}	V _{DD} ≈ 48 V, V _{GS} = 10 V, I _D = 50 A		70	_	nC
Gate-drain ("miller") charge		Q_{gd}			40		

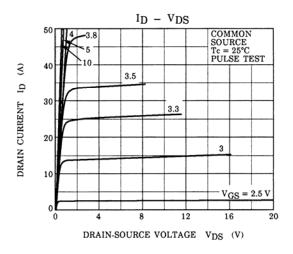
Source-Drain Ratings and Characteristics (Ta = 25°C)

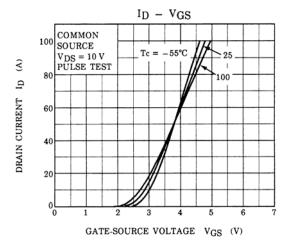
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	50	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	200	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 50 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 50 A, V _{GS} = 0 V		120	-	ns
Reverse recovered charge	Q _{rr}	dl _{DR} / dt = 50 A / μs		0.2	_	μC

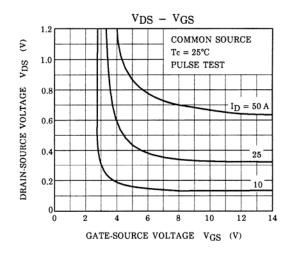
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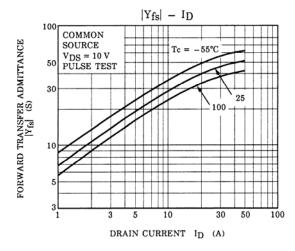


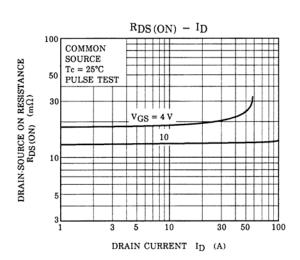


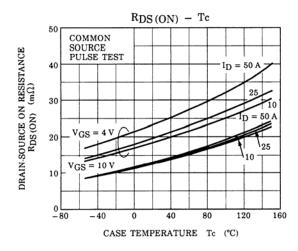


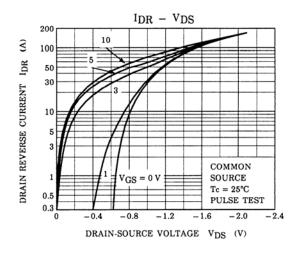


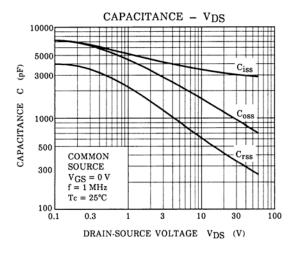


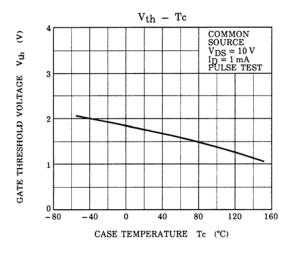


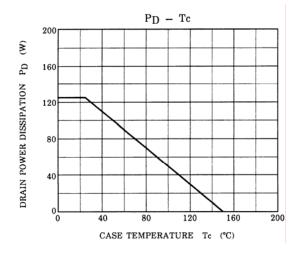


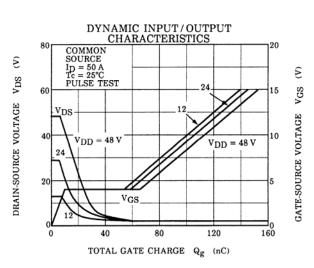




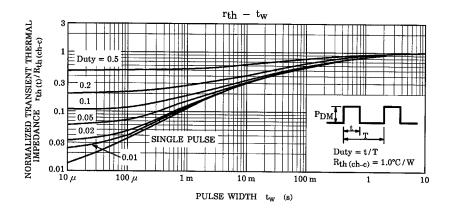


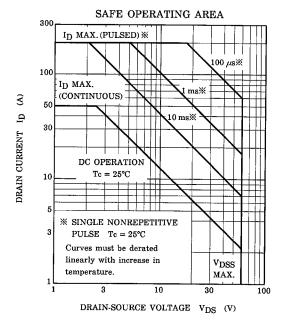


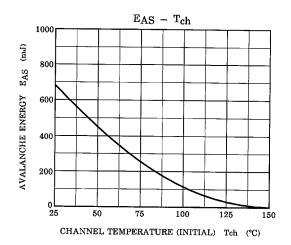


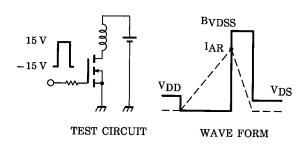


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$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 25~V,~L = 371~\mu H \end{aligned} \qquad E_{AS} &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right) \end{aligned}$$

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